Supporting information

Inverted thermal annealing of perovskite films: a method for enhancing photovoltaic device efficiency

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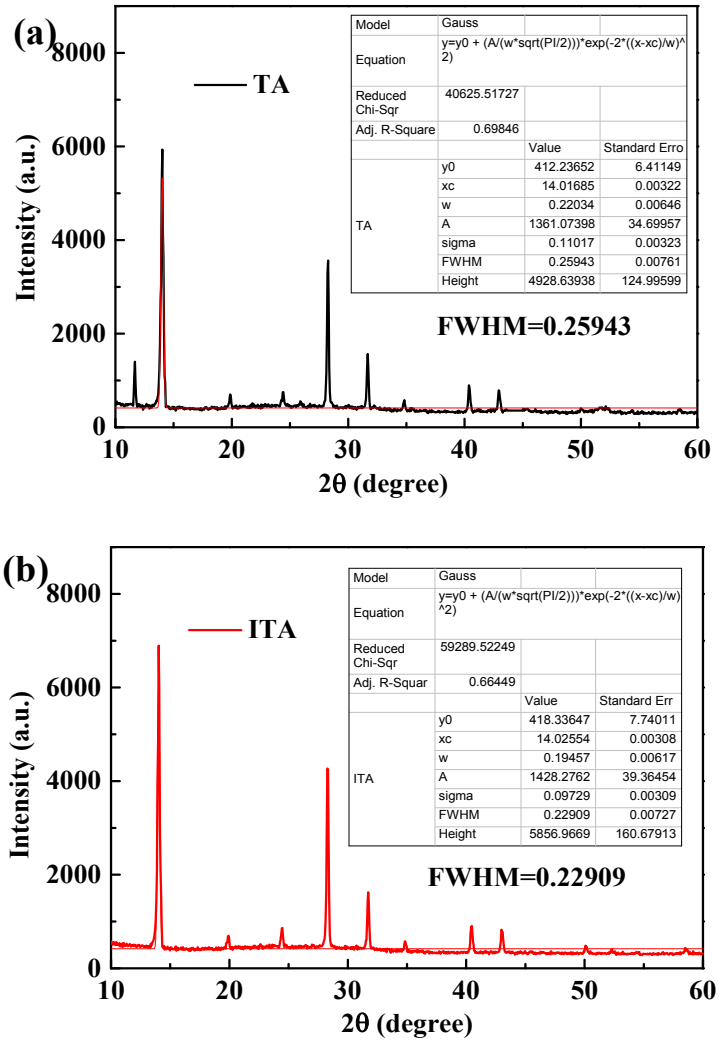

Figure S1. The FWHM results of the highest peak at 14.2° by fitting the original XRD datum of the perovskite films treated with TA (a) and ITA (b).

Table S1. EIS results of the PSCs treated with TA and ITA

Annealing	R_s (ohm cm^2)	R_{tr} (ohm cm^2)	R_{rec} (ohm cm^2)
TA	2.26	5.64	10.35
ITA	2.24	5.36	10.71